TOSHIBA RN6001

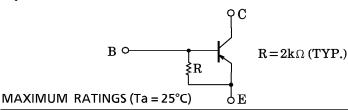
TOSHIBA TRANSISTOR SILICON PNP EPITAXIAL TYPE (PCT PROCESS)

RN6001

MOTOR DRIVE CIRCUIT APPLICATIONS. POWER AMPLIFIER APPLICATIONS. POWER SWITCHING APPLICATIONS.

- With Built-in Bias Resistors
- Simplify Circuit Design
- Reduce a Quantity of Parts and Manufacturing Process
- Small Flat Package
- P_C=1~2W (Mounted on Ceramic substrate)
- Complementary to RN5001

EQUIVALENT CIRCUIT



CHARACTERISTIC	SYMBOL	RATING	UNIT
Collector-Base Voltage	v_{CBO}	-30	V
Collector-Emitter Voltage	V_{CES}	-30	V
Emitter-Base Voltage	$V_{ m EBO}$	-5	V
Collector Current	$I_{\mathbf{C}}$	-2	Α
Base Current	I_{B}	-0.4	Α
Collector Power Dissipation	PC	500	mW
Collector Power Dissipation	PC*	1000	mW
Junction Temperature	Tj	150	°C
Storage Temperature Range	$T_{ m stg}$	-55~150	°C

* : Mounted on ceramic substrate (250mm²×0.8t)

ELECTRICAL CHARACTERISTICS (Ta = 25°C)

4.6 M 1.7 M 1.7 M 0.45 - 0.08 0.4 - 0.05 1.5 ± 0.1	AX.	0.41 0.42 0.05 0.05 0.08 0.08 0.08 0.08 0.08 0.08 0.09 0.08 0.09	1,6MAX. ±0.05
1. BASE	3	<i>(</i> неат	SINK)

Unit in mm

- COLLECTOR (HEAT SINK)
- 3. EMITTER

PW-MINI		
JEDEC	_	
EIAJ	SC-62	
TOSHIBA	2-5K1A	

Weight: 0.05g MARKING

Type Name

CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Collector Cut-off Current	ICBO	$V_{CB} = -30V, I_{E} = 0$		_	-0.1	μ A
Emitter Cut-off Current	$I_{ m EBO}$	$V_{EB} = -5V, I_C = 0$	-1.92	-2.5	-3.57	mA
Collector-Emitter Breakdown Voltage	V _{(BR)CES}	$I_C = -1mA$	-30	_	_	V
DC Current Gain	$h_{FE(1)}$	$V_{CE} = -2V, I_{C} = -0.5A$	100	_	320	
	$h_{FE(2)}$	$V_{CE} = -2V, I_{C} = -2.0A$	50	_		
Collector-Emitter Saturation Voltage	$V_{CE(sat)}$	$I_C = -1A, I_B = -0.05A$	l	_	-0.5	V
Base-Emitter Saturation Voltage	$V_{\mathrm{BE(sat)}}$	$I_C = -1A, I_C = -0.05A$	1		-1.2	V
Transition Frequency	${ m f_T}$	$V_{CE} = -2V, I_{C} = -0.5A$	l	120	_	MHz
Collector Output Capacitance	C_{ob}	$V_{CB} = -10V, I_{E} = 0, f = 1MHz$		40		pF
Resistor	R		1.4	2.0	2.6	$\mathbf{k}\Omega$

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